

# THE COMPUTATION OF DOUBLE-QUANTUM WELL ENERGY LEVEL IN SILICON-GERMANIUM COMPOUND (SI<sub>1-X</sub>GE<sub>X</sub>) WITH NUMERICAL METHOD

劉昌杰、韓斌

E-mail: 9125198@mail.dyu.edu.tw

## ABSTRACT

THIS WORK STUDIES MAINLY ON THE COMPUTATION OF DOUBLE QUANTUM WELL IN SILICON-GERMANIUM (SI<sub>1-X</sub>GE<sub>X</sub>) COMPOUND WITH NUMERICAL METHOD AND MODEL-SOLID THEORY. BECAUSE OF THE HETERO-STRUCTURE INTERFACE AND LATTICE CONSTANT MISMATCH BETWEEN THESE TWO ELEMENTS, THERE IS INDUCED STRAIN IN THE GEXSI<sub>1-X</sub> LAYER, WHICH CAN BE ADJUSTED THROUGH DIFFERENT CONCENTRATION (X) AND THE WELL WIDTH TO PRODUCE A 4-LEVEL SYSTEM. BY USING THIS 4-LEVEL SYSTEM, IT IS POSSIBLE TO PRODUCE TERA-HERTZ RADIATION EMISSION, WHICH IS IMPORTANT FOR PRACTICAL APPLICATION IN OPTICAL ENGINEERING.

Keywords : 無

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